

L Number	Hits	Search Text	DB	Time stamp
-	145	702/81.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 21:41
-	4655	quality with assurance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:28
-	36	(quality with assurance) and (inspection with item\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 21:43
-	742	(quality with assurance) and ((inspect\$3 or test\$3 or check\$3 or examin\$5) with (item\$1 or element\$1 or characteristic))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:29
-	574	((quality with assurance) and ((inspect\$3 or test\$3 or check\$3 or examin\$5) with (item\$1 or element\$1 or characteristic))) and (processor or microprocessor or computer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:34
-	530	((quality with assurance) and ((inspect\$3 or test\$3 or check\$3 or examin\$5) with (item\$1 or element\$1 or characteristic))) and (processor or microprocessor or computer) and (memor\$5 or stor\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:35
-	505	((quality with assurance) and ((inspect\$3 or test\$3 or check\$3 or examin\$5) with (item\$1 or element\$1 or characteristic))) and (processor or microprocessor or computer) and (memor\$5 or stor\$3)) and (display\$3 or print43 or output\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:35
-	152	((quality with assurance) and ((inspect\$3 or test\$3 or check\$3 or examin\$5) with (item\$1 or element\$1 or characteristic))) and (processor or microprocessor or computer) and (memor\$5 or stor\$3)) and (display\$3 or print43 or output\$4)) and ((item or meta or index or graded or degree) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:36
-	152	((quality with assurance) and ((inspect\$3 or test\$3 or check\$3 or examin\$5) with (item\$1 or element\$1 or characteristic))) and (processor or microprocessor or computer) and (memor\$5 or stor\$3)) and (display\$3 or print43 or output\$4)) and ((item or meta or index or graded or degree) with data)) and (substance or object or element\$1 or device or material\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:37
-	79	((quality with assurance) and ((inspect\$3 or test\$3 or check\$3 or examin\$5) with (item\$1 or element\$1 or characteristic))) and (processor or microprocessor or computer) and (memor\$5 or stor\$3)) and (display\$3 or print43 or output\$4)) and ((item or meta or index or graded or degree) with data)) and (substance or object or element\$1 or device or material\$1)) and (algorithm)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:39
-	36029	quality adj (assurance or control)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:16

-	11669	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:13
-	6300	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1))) and (processor or microprocessor or computer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:15
-	5185	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1))) and (processor or microprocessor or computer)) and (memor\$5 or stor\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:16
-	4688	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1))) and (processor or microprocessor or computer)) and (memor\$5 or stor\$3)) and (display\$3 or print43 or output\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:15
-	875	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1))) and (processor or microprocessor or computer)) and (memor\$5 or stor\$3)) and (display\$3 or print43 or output\$4)) and ((item or index or graded or characteristic) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:37
-	432	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1))) and (processor or microprocessor or computer)) and (memor\$5 or stor\$3)) and (display\$3 or print43 or output\$4)) and ((item or index or graded or characteristic) with data)) and ((substance or object or element\$1 or device or material\$1) with (inspect\$3 or test\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:39
-	22	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1))) and (processor or microprocessor or computer)) and (memor\$5 or stor\$3)) and (display\$3 or print43 or output\$4)) and ((item or index or graded or characteristic) with data)) and ((substance or object or element\$1 or device or material\$1) with (inspect\$3 or test\$3)) and (algorithm with data with process\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:57

-	1041	(((((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1))) and (processor or microprocessor or computer)) and (memor\$5 or stor\$3)) and (semiconductor or semi-conductor or photomask)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:57
-	51	(((((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3 or examin\$5 or monitor\$3 or evaluat\$3 or assess\$4) with (item\$1 or element\$1 or device\$1 or part\$1 or substnce or object\$1))) and (processor or microprocessor or computer)) and (memor\$5 or stor\$3)) and (semiconductor or semi-conductor or photomask)) and (algorithm with data with process\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 22:58
-	182	(quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:14
-	1	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (graded with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:14
-	151	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (processor or microprocessor or computer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:15
-	145	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (processor or microprocessor or computer)) and (display\$3 or print\$3 or output\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:15
-	145	((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (processor or microprocessor or computer)) and (display\$3 or print\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/16 23:15
-	143	(((((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (processor or microprocessor or computer)) and (display\$3 or print\$3)) and (memor\$5 or stor\$3 or database)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:03
-	40	(((((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (processor or microprocessor or computer)) and (display\$3 or print\$3)) and (memor\$5 or stor\$3 or database)) and (inspection with apparatus or item or method))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:04
-	1	(((((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (processor or microprocessor or computer)) and (display\$3 or print\$3)) and (memor\$5 or stor\$3 or database)) and (inspection with apparatus or item or method))) and (graded with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:04

-	1	(((((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (processor or microprocessor or computer)) and (display\$3 or print\$3)) and (memor\$5 or stor\$3 or database)) and (inspection with (apparatus or item or method))) and (grade)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:05
-	13	(((((quality adj (assurance or control)) and ((inspect\$3 or test\$3 or check\$3) with item\$1 with data)) and (processor or microprocessor or computer)) and (display\$3 or print\$3)) and (memor\$5 or stor\$3 or database)) and (inspection with (apparatus or item or method))) and (print\$3 with data with (substance or part\$1 or device\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:06
-	36337	quality adj (assurance or control or judgment)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:17
-	5392	(quality adj (assurance or control or judgment)) with (inspect43 or test\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:17
-	0	((quality adj (assurance or control or judgment)) with (inspect43 or test\$3)) and (photomask with pattern with region)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:18
-	2	((quality adj (assurance or control or judgment)) with (inspect43 or test\$3)) and (photomask with pattern)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:22
-	5	((quality adj (assurance or control or judgment)) with (inspect43 or test\$3)) and (graded with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/12/17 00:23